

metrologia



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Cover image: Inspired by a contour map of the joint photon detection function. **G Brida and C Novero**
Metrologia **40** S204 – S207

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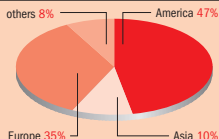
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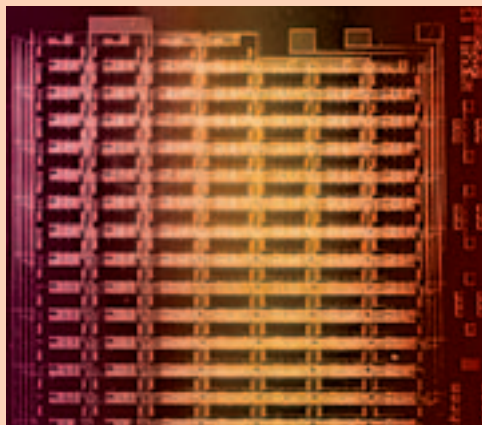
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Photograph of a quantum Hall array resistance standard sample.
W Poirier, A Bounouh, F Piquemal and J P André *Metrologia* 41 285 – 294



Photograph of the 1kg silicon sphere set in the vacuum mass comparator.
S Mizushima, M Ueki and K Fujii *Metrologia* 41 S68 – S74

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